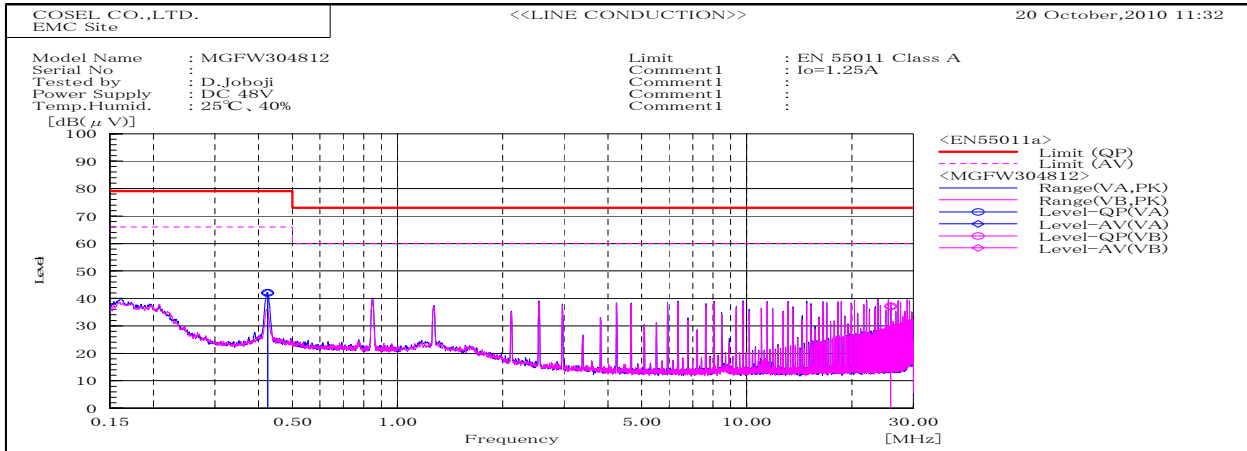
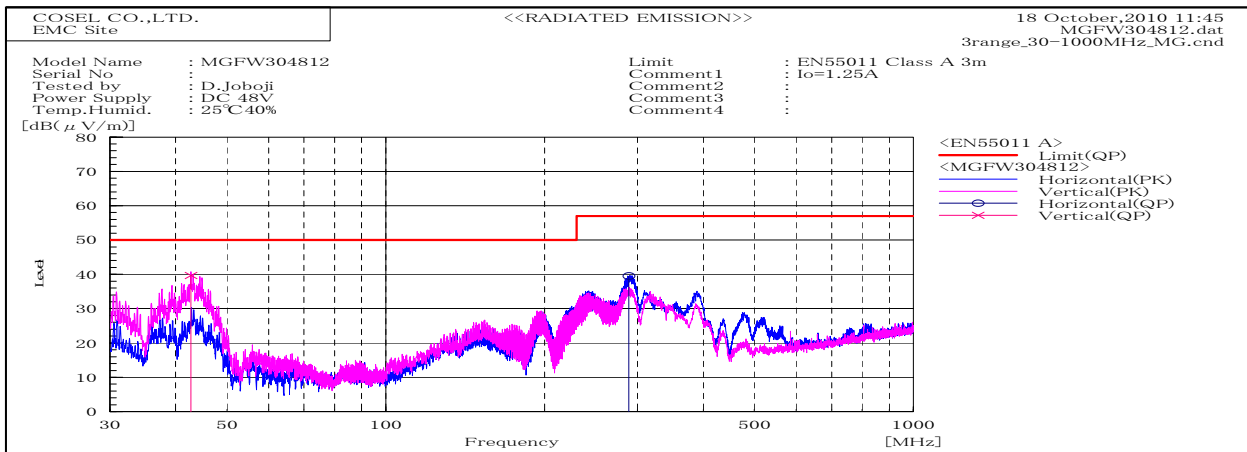


DATA SHEET		Date	20-Oct-10
Model	MGFW304812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.42466		VA	32	31.9	10.1	42.1	42	79	66	36.9	24	Pass	
25.8426		VB	26.1	26.1	11	37.1	37.1	73	60	35.9	22.9	Pass	

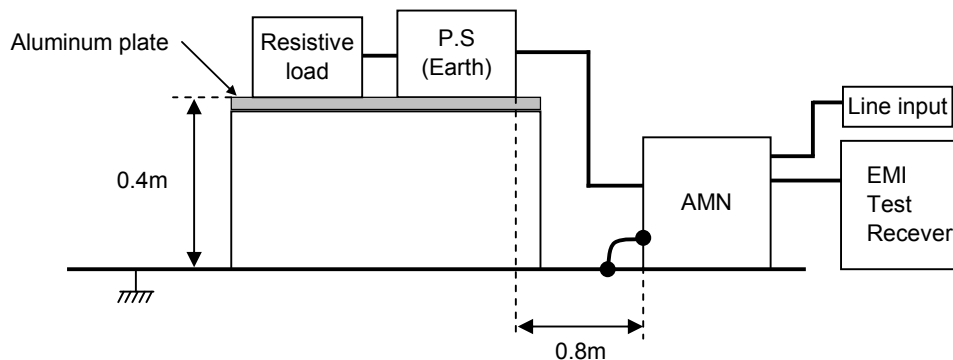


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
42.752	V	Stable	59.7	-20		39.7		50	10.3	Pass	101	123	
289.007	H	Stable	57.4	-17.9		39.5		57	17.5	Pass	117	169	

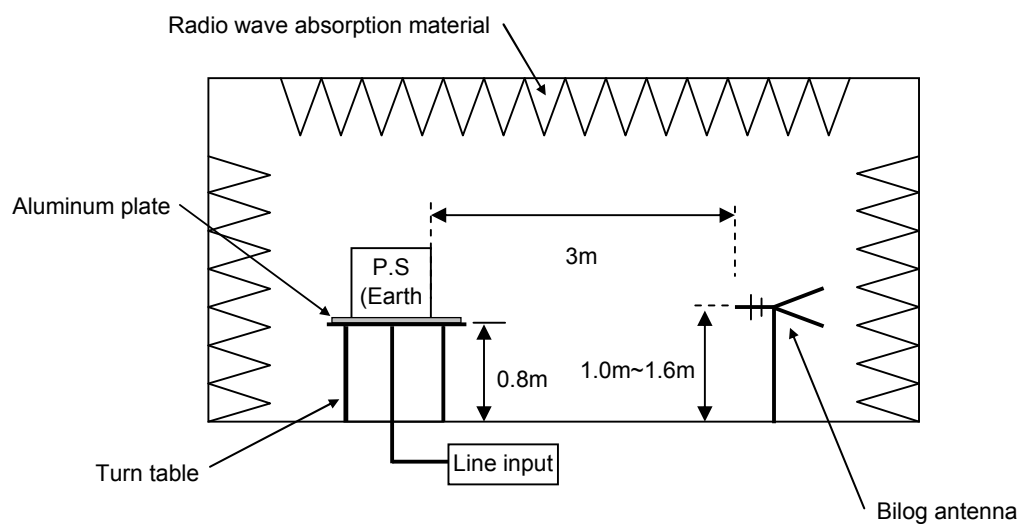
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
 Model Name : MGFS3048□□/MGFW3048□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

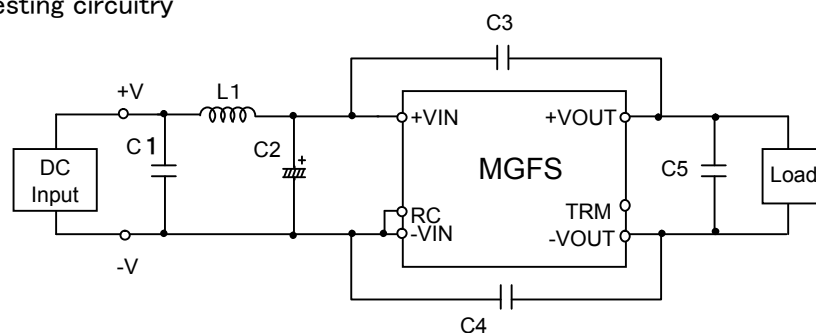


Fig.1 Testing circuitry 1

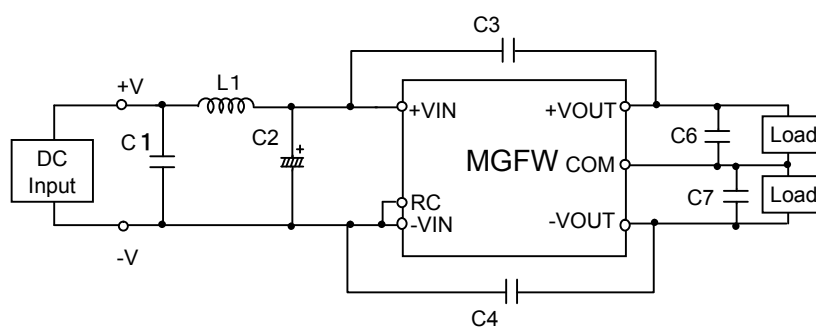


Fig.2 Testing circuitry 2

L1	: 4.7uH	CI8C-4R7	(KORIN ELECTRONICS)
C1	: 100V	2.2 μ F	Ceramic Capacitor
C2	: 80V	47 μ F	Electrolytic Capacitor
C3,C4	: 2kV	1000pF	Ceramic Capacitor
C5,C6,C7	: 25V	22 μ F	Ceramic Capacitor